

FEATURES

2 pF off capacitance
 1 pC charge injection
 33 V supply range
 120 Ω on resistance
 Fully specified at ± 15 V/12 V
 3 V logic compatible inputs
 Rail-to-rail operation
 Break-before-make switching action
 16-lead TSSOP and 4 mm $\times$ 4 mm LFCSP packages
 Typical power consumption (< 0.03 μ W)

APPLICATIONS

Audio and video routing
 Automatic test equipment
 Data acquisition systems
 Battery-powered systems
 Sample-and-hold systems
 Communication systems

GENERAL DESCRIPTION

The ADG1208 and ADG1209 are monolithic μ COS analog multiplexers comprising eight single channels and four differential channels, respectively. The ADG1208 switches one of eight inputs to a common output as determined by the 3-bit binary address lines A0, A1, and A2. The ADG1209 switches one of four differential inputs to a common differential output as determined by the 2-bit binary address lines A0 and A1. An EN input on both devices is used to enable or disable the device. When disabled, all channels are switched OFF.

The μ COS (industrial-CMOS) modular manufacturing process combines high-voltage CMOS (complementary metal-oxide semiconductor) and bipolar technologies. It enables the development of a wide range of high performance analog ICs capable of 33-V operation in a footprint that no other generation of high-voltage parts has been able to achieve. Unlike analog ICs using conventional CMOS processes, μ COS components can tolerate high supply voltages, while providing increased performance, dramatically lower power consumption, and reduced package size.

FUNCTIONAL BLOCK DIAGRAMS

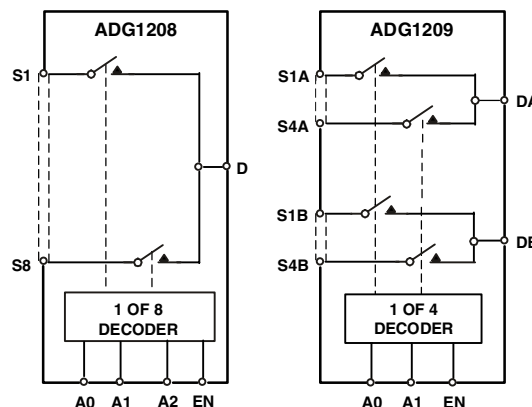


Figure 1.

The ultralow capacitance and charge injection of these multiplexers make them ideal solutions for data acquisition and sample-and-hold applications, where low glitch and fast settling are required. Fast switching speed coupled with high signal bandwidth make the parts suitable for video signal switching. μ COS construction ensures ultralow power dissipation, making the parts ideally suited for portable and battery powered instruments.

PRODUCT HIGHLIGHTS

1. 2 pF off capacitance (± 15 V supply).
2. 1 pC charge injection.
3. 3 V logic compatible digital input $V_{IH} = 2.0$ V, $V_{IL} = 0.8$ V.
4. 16-lead TSSOP and 4 mm $\times$ 4 mm LFCSP package.

Rev. PrA

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REVISION HISTORY

SPECIFICATIONS

DUAL SUPPLY¹

$V_{DD} = +15\text{ V} \pm 10\%$, $V_{SS} = -15\text{ V} \pm 10\%$, GND = 0 V, unless otherwise noted.

Table 1.

Parameter	+25°C	−40°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH				
Analogue Signal Range		V_{SS} to V_{DD}	V	
R_{ON}	140		Ω typ	$V_D = \pm 10\text{ V}$, $I_S = -10\text{ mA}$
	160		Ω max	
R_{ON} Flatness	55		Ω typ	$V_D = +10\text{ V}$, -10 V
			Ω max	
ΔR_{ON}	5		Ω typ	$V_D = +10\text{ V}$, -10 V
			Ω max	
LEAKAGE CURRENTS				
Source OFF Leakage I_S (OFF)	± 0.01		nA typ	$V_D = \pm 10\text{ V}$, $V_S = -10\text{ V}$; Test Circuit 2
	± 0.5	± 5	nA max	± 0.5
Drain OFF Leakage I_D (OFF)				$V_D = \pm 10\text{ V}$; $V_S = \pm 10\text{ V}$;
ADG1208	± 1	± 10	nA max	Test Circuit 3
ADG1209	± 1	± 5	nA max	
Channel ON Leakage I_D , I_S (ON)				$V_S = V_D = \pm 10\text{ V}$;
ADG1208	± 1	± 10	nA max	Test Circuit 4
ADG1209	± 1	± 5	nA max	
DIGITAL INPUTS				
Input High Voltage, V_{INH}		2.0	V min	
Input Low Voltage, V_{INL}		0.8	V max	
Input Current				
I_{INL} or I_{INH}	± 0.005		μA max	$V_{IN} = V_{INL}$ or V_{INH}
		± 0.5	μA max	
C_{IN} , Digital Input Capacitance	5		pF typ	
DYNAMIC CHARACTERISTICS²				
$t_{TRANSITION}$	80	120	ns typ	$R_L = 300\ \Omega$, $C_L = 35\text{ pF}$;
		250	ns max	$V_{S1} = \pm 10\text{ V}$, $V_{S8} = \pm 10\text{ V}$;
				Test Circuit 5
T_{BBM}	10	10	ns typ	$R_L = 300\ \Omega$, $C_L = 35\text{ pF}$;
		1	ns min	$V_S = 10\text{ V}$; Test Circuit 6
$t_{ON(EN)}$	85	125	ns typ	$R_L = 300\ \Omega$, $C_L = 35\text{ pF}$;
	150	225	ns max	$V_S = 5\text{ V}$; Test Circuit 7
$t_{OFF(EN)}$	40	65	ns typ	$R_L = 300\ \Omega$, $C_L = 35\text{ pF}$;
		150	ns max	$V_S = 5\text{ V}$; Test Circuit 7
Charge Injection	1		pC typ	$V_S = 0\text{ V}$, $R_S = 0\ \Omega$, $C_L = 10\text{ nF}$;
				Test Circuit 8
OFF Isolation	75		dB typ	$R_L = 1\text{ k}\Omega$, $f = 100\text{ kHz}$;
				$V_{EN} = 0\text{ V}$; Test Circuit 9
Channel-to-Channel Crosstalk	85		dB typ	$R_L = 1\text{ k}\Omega$, $f = 100\text{ kHz}$;
				Test Circuit 10
Total Harmonic Distortion, THD + N	0.002		% typ	$R_L = 600\ \Omega$, 5 V rms ; $f = 20\text{ Hz}$ to 20 kHz
−3 dB Bandwidth	700		MHz typ	$R_L = 300\ \Omega$, $C_L = 5\text{ pF}$; Test Circuit 10
				Test Circuit 10

Parameter	+25°C	–40°C to +125°C	Unit	Test Conditions/Comments
C _S (OFF)	1.5		pF typ	
C _D (OFF)				
ADG1208	11		pF typ	
ADG1209	6		pF typ	
C _D , C _S (ON)				
ADG1208	15		pF typ	
ADG1209	8		pF typ	
POWER REQUIREMENTS				V _{DD} = +16.5 V, V _{SS} = –16.5 V
I _{DD}	0.001		μA typ	Digital inputs= 0 V or V _{DD}
		5	μA max	
I _{DD}	150		μA typ	Digital inputs= 5 V
		300	μA max	
I _{SS}	0.001		μA typ	Digital inputs= 0 V or V _{DD}
		5	μA max	
I _{GND}	0.001		μA typ	Digital inputs= 0 V or V _{DD}
		5	μA max	
I _{GND}	150		μA typ	Digital inputs= 5 V
		300	μA max	

¹ Temperature ranges are as follows: B Version: –40°C to +125°C.

² Guaranteed by design, not subject to production test.

SINGLE SUPPLY¹

V_{DD} = 12 V V ± 10%, V_{SS} = 0 V, GND = 0 V, unless otherwise noted.

Table 2.

Parameter	+25°C	–40°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH				
Analog Signal Range		0 to V _{DD}	V	
R _{ON}	300		Ω typ	V _D = 3 V, 10 V, I _S = –1 mA
			Ω max	
R _{ON} Flatness	150		Ω typ	V _D = 3 V, 10 V, I _S = –1 mA
			Ω max	
ΔR _{ON}	5		Ω typ	V _D = 3 V, 10 V, I _S = –1 mA
			Ω max	
LEAKAGE CURRENTS				
Source OFF Leakage I _S (OFF)	±0.01		nA typ	V _D = ±10 V, V _S = –10 V; Test Circuit 2
	±0.5	±5	nA max	±0.5
Drain OFF Leakage I _D (OFF)				V _D = ±10 V; V _S = ±10 V;
ADG1208	±1	±10	nA max	Test Circuit 3
ADG1209	±1	±5	nA max	
Channel ON Leakage I _D , I _S (ON)				V _S = V _D = 8 V/0 V;
ADG1208	±1	±10	nA max	Test Circuit 4
ADG1209	±1	±5	nA max	
DIGITAL INPUTS				
Input High Voltage, V _{INH}		2.0	V min	
Input Low Voltage, V _{INL}		0.8	V max	
Input Current				

Parameter	+25°C	–40°C to +125°C	Unit	Test Conditions/Comments
I_{INL} or I_{INH}		± 10	μA max	$V_{IN} = 0$ or V_{DD}
C_{IN} , Digital Input Capacitance	8		pF typ	$f = 1$ MHz
DYNAMIC CHARACTERISTICS ²				
$t_{TRANSITION}$	130		ns typ	$R_L = 300 \Omega$, $C_L = 35$ pF; $V_{S1} = 8$ V/0 V, $V_{S8} = 0$ V/8 V; Test Circuit 5
T_{BBM}	10		ns typ	$R_L = 300 \Omega$, $C_L = 35$ pF;
		1	ns min	$V_S = 5$ V; Test Circuit 6
t_{ON} (EN)	140		ns typ	$R_L = 300 \Omega$, $C_L = 35$ pF; $V_S = 5$ V; Test Circuit 7

Parameter	+25°C	–40°C to +125°C	Unit	Test Conditions/Comments
DYNAMIC CHARACTERISTICS ²				
t_{OFF} (EN)	60		ns typ	$R_L = 300\ \Omega$, $C_L = 35\ \text{pF}$; $V_S = 5\ \text{V}$; Test Circuit 7
Charge Injection	5		pC typ	$V_S = 0\ \text{V}$, $R_S = 0\ \Omega$, $C_L = 10\ \text{nF}$; Test Circuit 8
OFF Isolation	–75		dB typ	$R_L = 1\ \text{k}\Omega$, $f = 100\ \text{kHz}$; $V_{\text{EN}} = 0\ \text{V}$; Test Circuit 9
Channel-to-Channel Crosstalk	85		dB typ	$R_L = 1\ \text{k}\Omega$, $f = 100\ \text{kHz}$; Test Circuit 10
Total Harmonic Distortion, THD + N	0.002		% typ	$R_L = 600\ \Omega$, $5\ \text{V rms}$; $f = 20\ \text{Hz}$ to $20\ \text{kHz}$
–3 dB Bandwidth	50		MHz typ	$R_L = 300\ \Omega$, $C_L = 5\ \text{pF}$; Test Circuit 10
C_S (OFF)	2		pF typ	$f = 1\ \text{MHz}$
C_D (OFF)				$f = 1\ \text{MHz}$
ADG1208	11		pF typ	
ADG1209	6		pF typ	
C_D , C_S (ON)				$f = 1\ \text{MHz}$
ADG1208	15		pF typ	
ADG1209	8		pF typ	
POWER REQUIREMENTS				$V_{\text{DD}} = 13.2\ \text{V}$
I_{DD}		1	$\mu\text{A typ}$	Digital inputs= 0 V or V_{DD}
		5	$\mu\text{A max}$	
I_{DD}	150		$\mu\text{A typ}$	Digital inputs= 5
		300	$\mu\text{A max}$	

¹ Temperature ranges are as follows: B Version: –40°C to +125°.

² Guaranteed by design, not subject to production test.

ABSOLUTE MAXIMUM RATINGS

Absolute maximum ratings $T_A = 25^\circ\text{C}$, unless otherwise noted.

Table 3.

Parameter	Rating
V_{DD} to V_{SS}	36 V
V_{DD} to GND	-0.3 V to +25 V
V_{SS} to GND	+0.3 V to -25 V
Analog, Digital Inputs ¹	$V_{SS} - 0.3$ V to $V_{DD} + 0.3$ V or 20 mA, whichever occurs first
Continuous Current, S or D	30 mA
Peak Current, S or D (Pulsed at 1 ms, 10% Duty Cycle max)	100 mA
Operating Temperature Range	
Industrial (B Version)	-40° C to +85°C
Automotive (Y Version)	-40° C to +125°C
Storage Temperature Range	-65° C to +150°C
Junction Temperature	150°C
TSSOP Package, Power Dissipation	450 mW
θ_{JA} , Thermal Impedance	150.4°C/W
θ_{JC} , Thermal Impedance	50°C/W
LFCSP, Package, Power Dissipation	450 mW
Lead Temperature, Soldering	
Vapor Phase (60 sec)	215°C
Infrared (15 sec)	220°C

¹ Overvoltages at A, EN, S, or D are clamped by internal diodes. Current should be limited to the maximum ratings given

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those listed in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Only one absolute maximum rating may be applied at any one time.

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



PIN CONFIGURATIONS

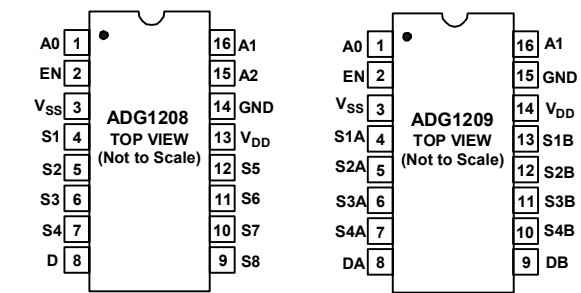


Figure 2. Pin Configurations—TSSOP

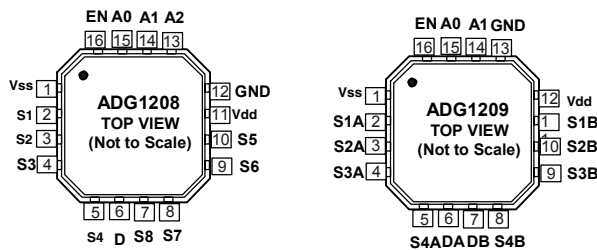


Figure 3. Pin Configurations – 4mm x4mm LFCSP

Table 4. ADG1208 Truth Table

A2	A1	A0	EN	ON SWITCH
X	X	X	0	NONE
0	0	0	1	1
0	0	1	1	2
0	1	0	1	3
0	1	1	1	4
1	0	0	1	5
1	0	1	1	6
1	1	0	1	7
1	1	1	1	8

Table 5. ADG1209 Truth Table

AI	A0	EN	ON SWITCH PAIR
X	X	0	NONE
0	0	1	1
0	1	1	2
1	0	1	3
1	1	1	4

TERMINOLOGY

Table 6.

Mnemonic	Description
V_{DD}	Most positive power supply potential.
V_{SS}	Most negative power supply potential in dual supplies. In single supply applications, it may be connected to ground.
GND	Ground (0 V) reference.
R_{ON}	Ohmic resistance between D and S.
ΔR_{ON}	Difference between the R_{ON} of any two channels.
I_S (OFF)	Source leakage current when the switch is off.
I_D (OFF)	Drain leakage current when the switch is off.
I_D, I_S (ON)	Channel leakage current when the switch is on.
V_D (vs)	Analog voltage on terminals D, S.
C_S (OFF)	Channel input capacitance for OFF condition.
C_D (OFF)	Channel output capacitance for OFF condition.
C_D, C_S (ON)	ON switch capacitance.
C_{IN}	Digital input capacitance.
t_{ON} (EN)	Delay time between the 50% and 90% points of the digital input and switch ON condition.
t_{OFF} (EN)	Delay time between the 50% and 90% points of the digital input and switch OFF condition.
$t_{TRANSITION}$	Delay time between the 50% and 90% points of the digital inputs and the switch ON condition when switching from one address state to another.
t_{OPEN}	OFF time measured between the 80% point of both switches when switching from one address state to another.
V_{INL}	Maximum input voltage for Logic 0.
V_{INH}	Minimum input voltage for Logic 1.
I_{INL} (I_{INH})	Input current of the digital input.
I_{DD}	Positive supply current.
I_{SS}	Negative supply current.
Off Isolation	A measure of unwanted signal coupling through an OFF channel.
Charge Injection	A measure of the glitch impulse transferred from the digital input to the analog output during switching.
Bandwidth	The frequency at which the output is attenuated by 3dBs.
On Response	The frequency response of the "ON" switch.
THD + N	The ratio of the harmonic amplitude plus noise of the signal to the fundamental.

TYPICAL PERFORMANCE CHARACTERISTICS

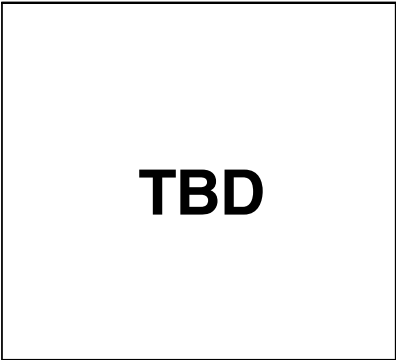


Figure 4. On Resistance as a Function of $V_D(V_S)$ for Single Supply

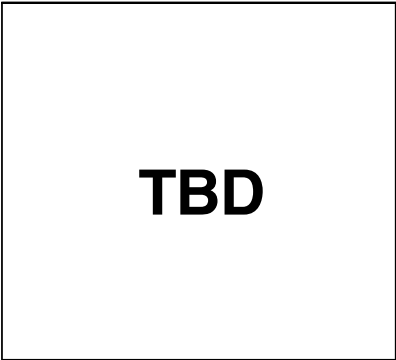


Figure 7. On Resistance as a Function of $V_D(V_S)$ for Different Temperatures, Single Supply

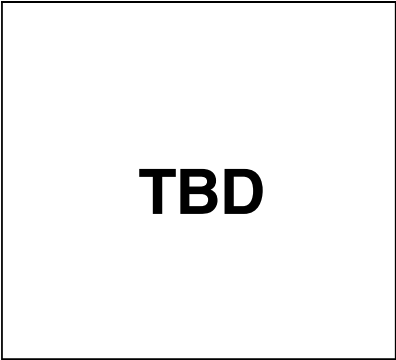


Figure 5. On Resistance as a Function of $V_D(V_S)$ for Dual Supply

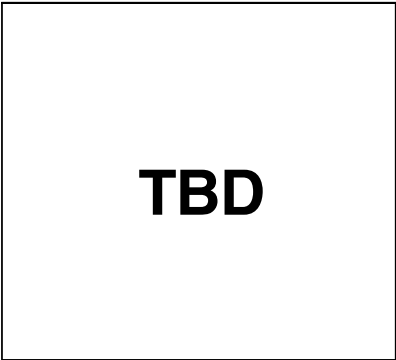


Figure 8. On Resistance as a Function of $V_D(V_S)$ for Different Temperatures, Dual Supply

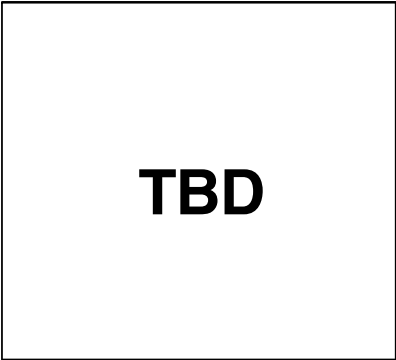


Figure 6. On Resistance as a Function of $V_D(V_S)$ for Different Temperatures, Single Supply

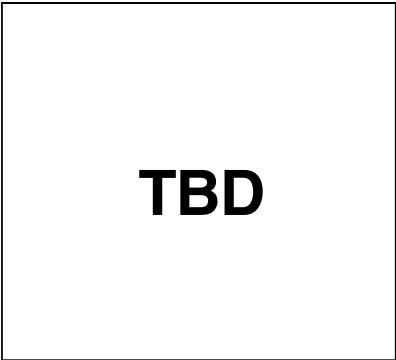


Figure 9. Leakage Currents as a Function of $V_D(V_S)$

TBD

Figure 10. Leakage Currents as a function of Temperature

TBD

Figure 14. Off Isolation vs. Frequency

TBD

Figure 11. Supply Currents vs. Input Switching Frequency

TBD

Figure 15. Crosstalk vs. Frequency

TBD

Figure 12. Charge Injection vs. Source Voltage

TBD

Figure 16. On Response vs. Frequency

TBD

Figure 13. TON/TOFF Times vs. Temperature)

TBD

Figure 17. THD + N vs. Frequency

TEST CIRCUITS

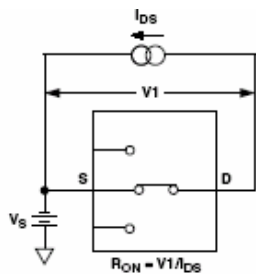
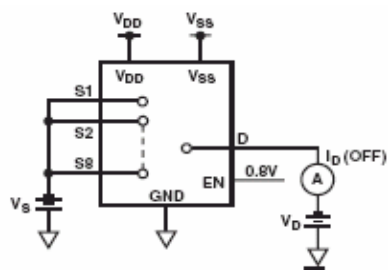
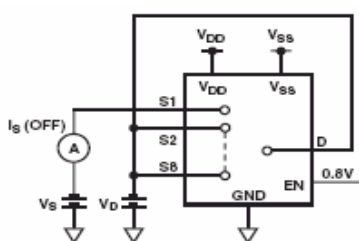
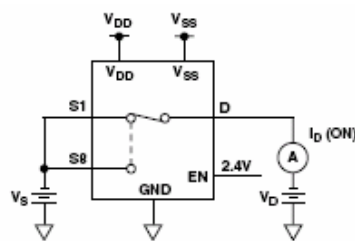
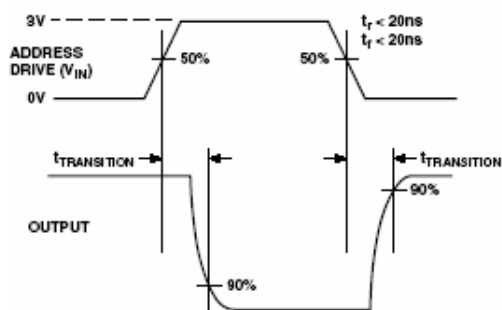
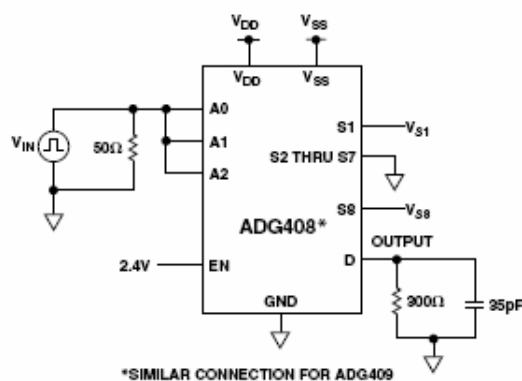


Figure 18. Test Circuit 1. On Resistance

Figure 20. Test Circuit 3. I_D (OFF)Figure 19. Test Circuit 2. I_S (OFF)Figure 21. Test Circuit 4. I_D (ON)Figure 22. Test Circuit 5. Switching Time of Multiplexer, $t_{\text{TRANSITION}}$ Figure 23. Test Circuit 6. Break-Before-Make Delay, t_{OPEN}

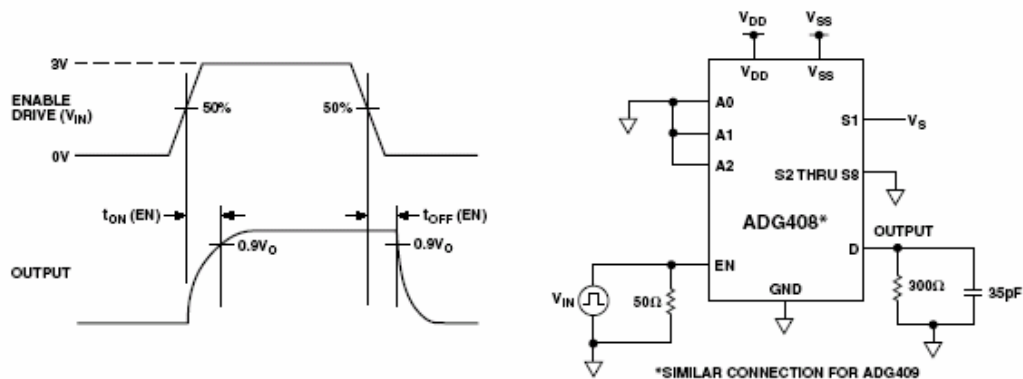


Figure 24. Test Circuit 7. Enable Delay, $t_{ON} (EN)$, $t_{OFF} (EN)$

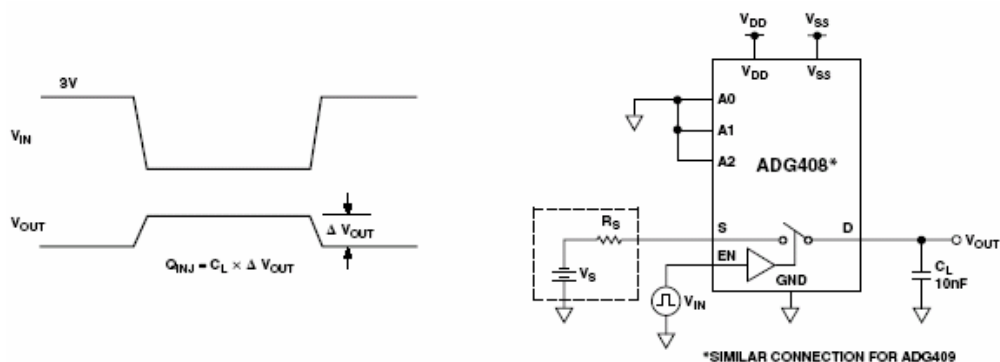


Figure 25. Test Circuit 8. Charge Injection

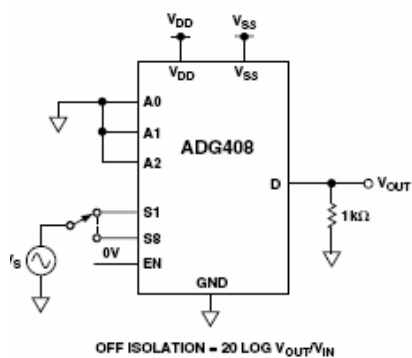


Figure 26. Test Circuit 9. OFF Isolation

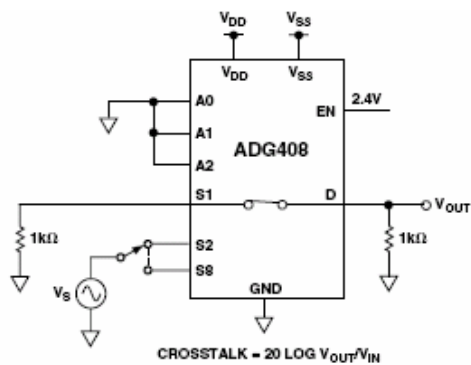


Figure 27. Test Circuit 10. Channel-to-Channel Crosstalk

OUTLINE DIMENSIONS

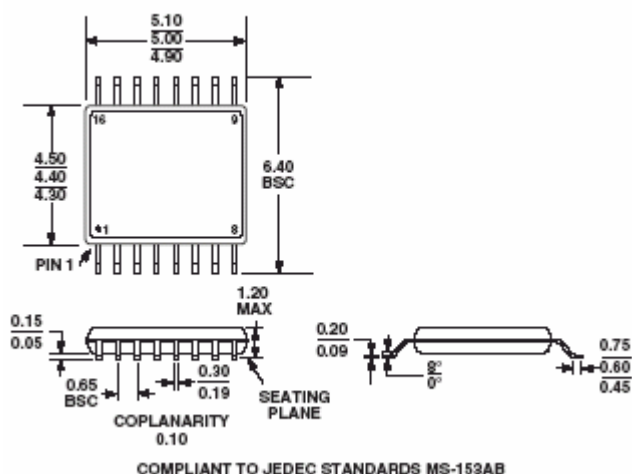
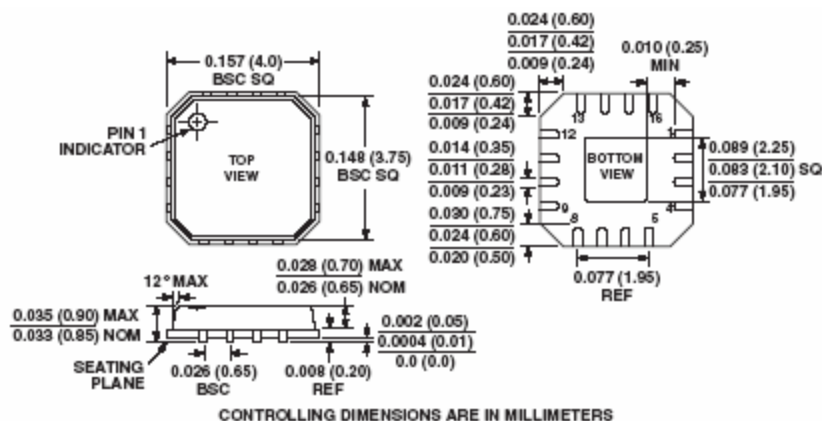


Figure 28. 16-Lead Thin Shrink Small Outline Package [TSSOP] (RU-16)

Figure 29. 16-Lead Lead Frame Chip Scale Package [LFCSPP]
4mm x 4mm (CP-16)

Dimensions shown in inches and (millimeters)

ORDERING GUIDE

Model	Temperature Range	Description	Package Option
ADG1208YRU	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1209YRU	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1209YCP	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	CP-16
ADG1209YCP	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	CP-16

NOTES

NOTES